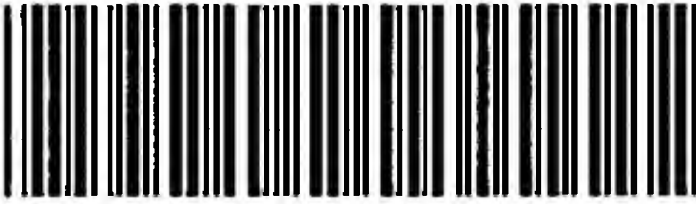


Search Notes 	Application No.	Applicant(s)	
	10/604,244	TAI ET AL.	
	Examiner	Art Unit	
	Toan M. Le	2863	

SEARCHED			
Class	Subclass	Date	Examiner
702	84	5/16/2005	TL
700	109	5/16/2005	TL
438	14	5/16/2005	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
702	84	5/16/2005	TL
438	14	5/16/2005	TL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Wafer In-line Yield Prediction	5/16/2005	TL
Wafer Yield Analysis; Statistical; Regression; Sample	5/16/2005	TL
Wafer Quality Control Analysis; Parameter; Lot; Sample	5/16/2005	TL
Quality Control, Sample, Parameter, Search, Database, Analyzing, Correlating, Wafer	5/16/2005	TL
Wafer, In-Line, Test, Data Mining, Yield	5/16/2005	TL
East, Web, and NPL search		